

Notice of References Cited	Application/Control No. 10/715,376	Applicant(s)/Patent Under Reexamination SUN ET AL.	
	Examiner Thinh T. Nguyen	Art Unit 2818	Page 1 of 1

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*	B	US-6,721,201	04-2004	Ikeda, Takashi	365/158
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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